



Going Beyond a Qualification Report: Power Cycling and Lifetime Modeling

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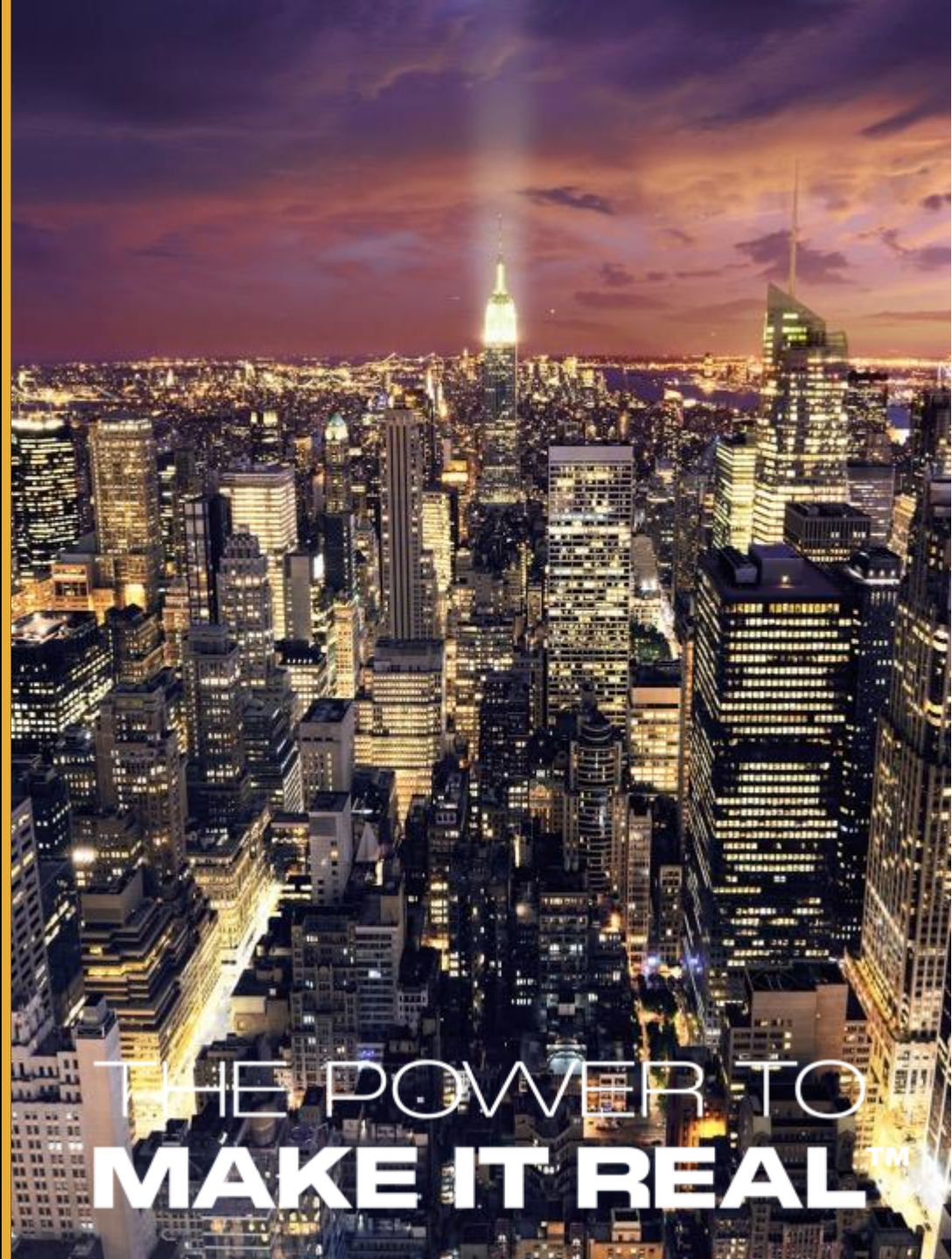
**Bodo's
Wide Bandgap
Event 2025**

Making WBG Designs Happen

sic

ELECTRIFICATION, DIGITALIZATION & AI ARE GLOBAL TRENDS THAT ARE SHAPING OUR TODAY AND TOMORROW

*High-voltage applications are NOT
created equal and require
application-optimized solutions.*





Each application has a different mission profile

Maximize the useful life is our mission

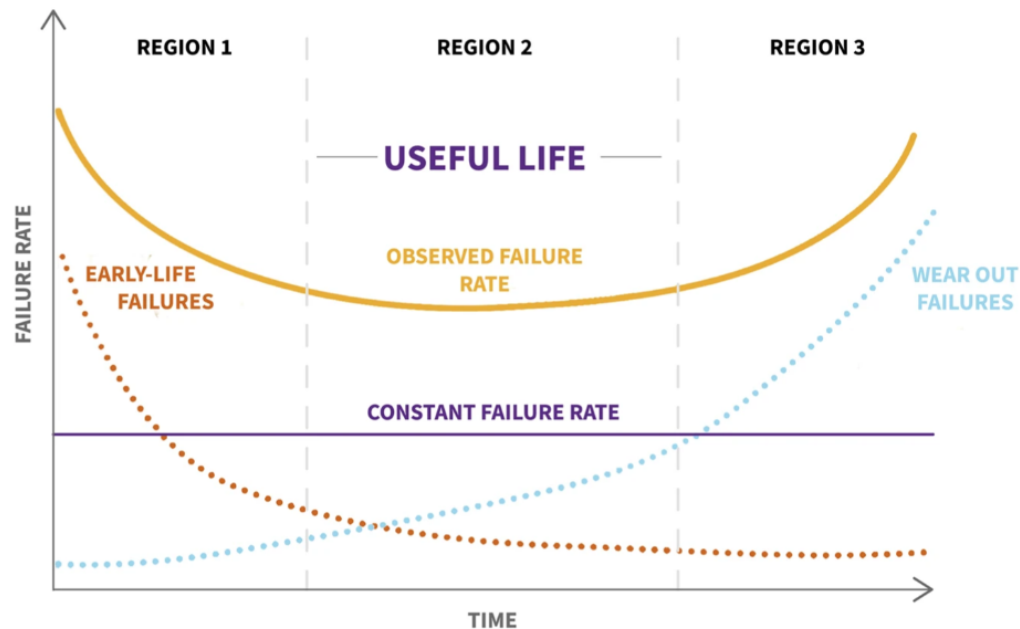
Wolfspeed

End systems enabled by SiC are now vast and entrenched, covering a multitude of voltage and power levels, many different package types and many differing mission profiles and long-term reliability requirements.

So much more than a qualification report, today's Silicon Carbide has to have proven application specific end system durability and ruggedness.



Delivering the next level of ruggedness at every stage of product life cycle



The lifecycle of reliability and failure rates of products

- **Early Failure:** Excellence in material defectivity and manufacturing imperfections control. Extended qualification test are further reducing the early failures
- **Constant (Random) Failures:** Enhanced MOSFET device structure and optimized Gate Oxide design are improving by orders of magnitude the constant failures.
- **Wear Out Failures:** Application optimized and easy to control devices are reducing the lifetime stress. Material and interconnection improvements are increasing the number of power cycles for a better durability

$$T_j = T_a + \overbrace{(R_{th} * P)}^{\Delta T}$$

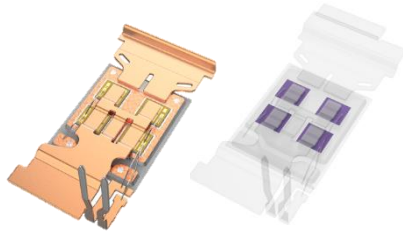
R_{th}

Packaging
Thermals

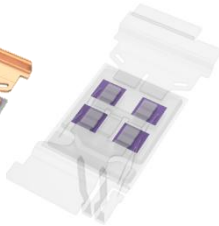
Die attach
technology



Pin Fin



Clip Topside
Interconnection

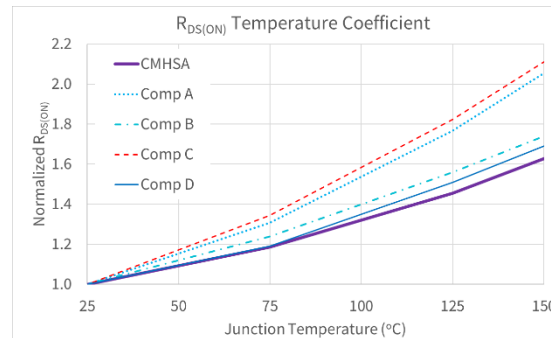


Device & Package
Sintering

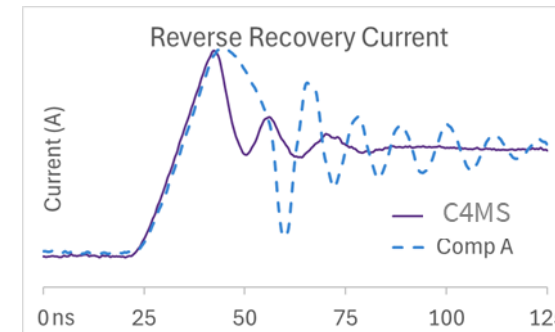
Total Losses

Die Performance

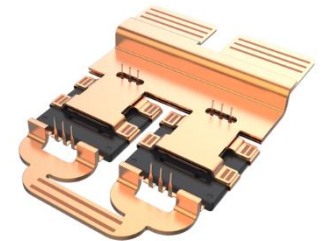
Conduction Losses



Switching Losses



Packaging Parasitic

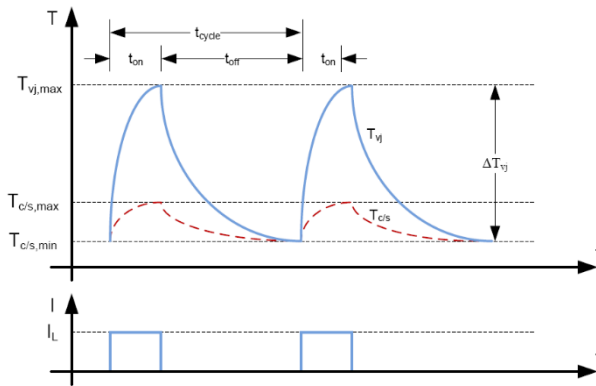


Low Loop
Inductance

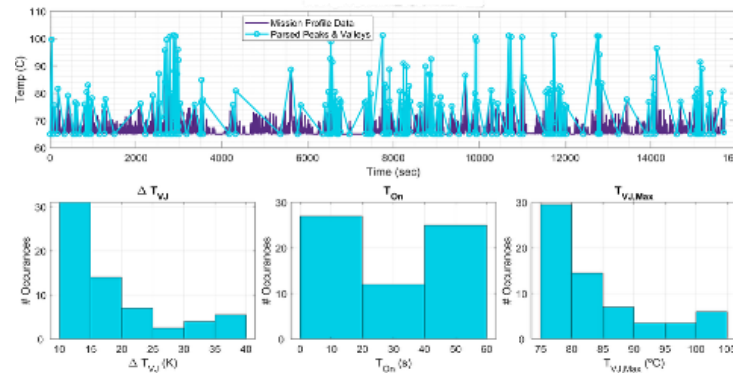
Power cycling analysis has emerged as one of the most relevant figures of merit for system lifetime in real-world applications

Lifetime model derived from power cycling can predict device lifetime in customer-specific applications

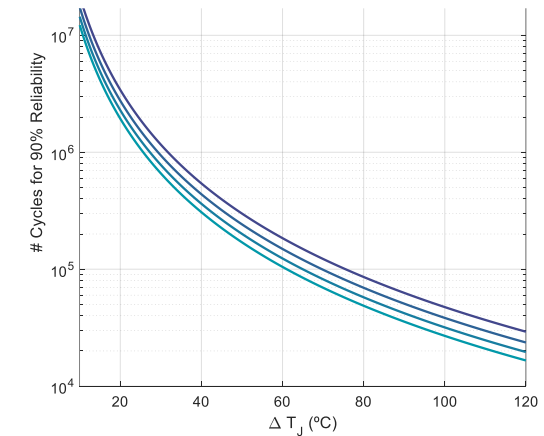
Power Cycling Testing Model Definition



Mission Profile Analysis

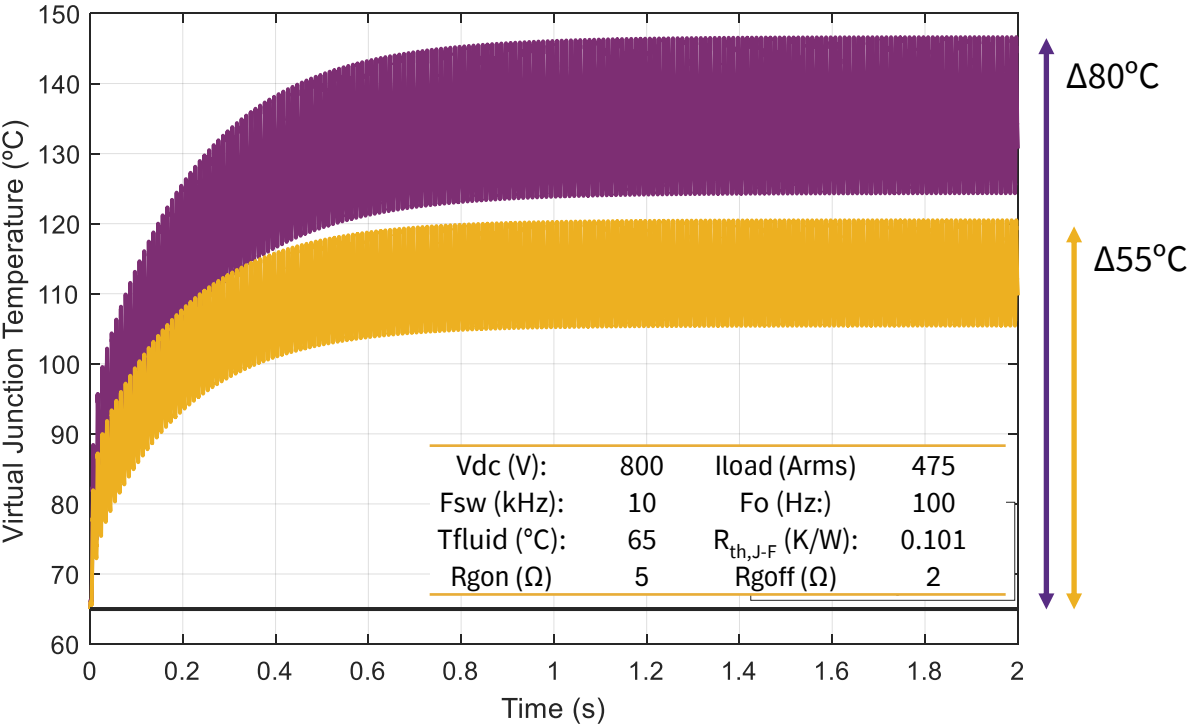


Lifetime Estimation

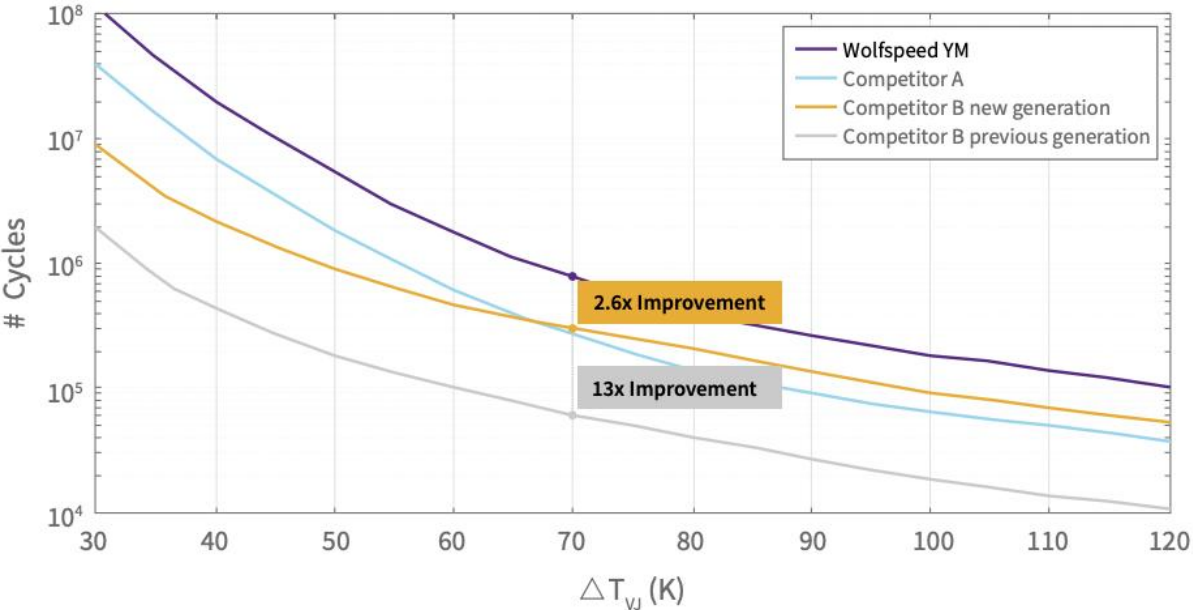


POWER MODULE LIFETIME ESTIMATION

The practical implementation of power cycling analysis extends far beyond laboratory characterization, providing system designers with quantitative tools **for optimizing application's lifetime, predicting maintenance requirements, and minimizing total cost of ownership.**

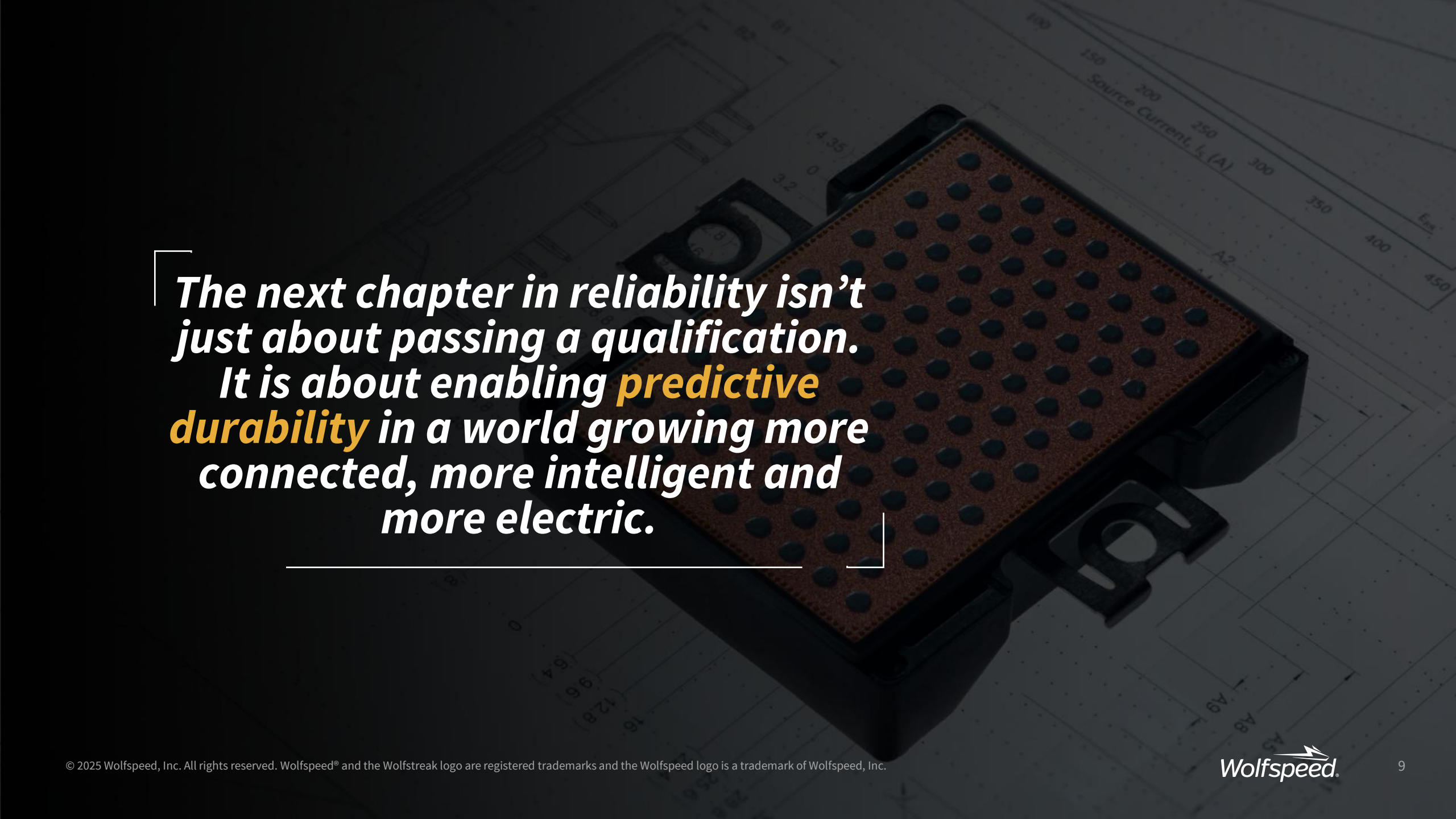


Combination of improved package materials and die attachment together with Wolfspeed Gen 4 die superior capabilities, the ΔT is reduced **from 80°C to 55°C** for the same application



Using cutting-edge packaging technology including sintered die attach and epoxy encapsulant material and copper clip interconnect enabling **3 times more power cycles**





*The next chapter in reliability isn't just about passing a qualification. It is about enabling **predictive durability** in a world growing more connected, more intelligent and more electric.*